Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/667,511	MIYAMORI ET AL.
Examiner	Art Unit

Binh X. Tran

1765

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Class	Subclass	Date	Examiner
438	697	9/13/2005	вт
438	703	9/13/2005	ВТ
438	722	9/13/2005	ВТ
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	DATE	EXMR
Search keywords and inventor's name using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	9/13/2005	вт
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